

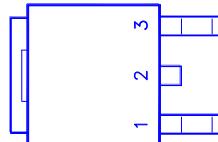
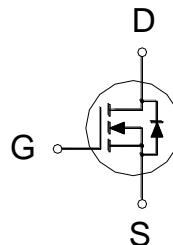
NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P0706BD

TO-252

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	7.5mΩ	87A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	60	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ²	$T_C = 25^\circ\text{C}$	I_D	87	A
	$T_C = 100^\circ\text{C}$		62	
Pulsed Drain Current ¹		I_{DM}	150	A
Avalanche Current		I_{AS}	59	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	172	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	115	W
	$T_C = 100^\circ\text{C}$		57	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 175	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Package limitation current is 55A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	μA
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 15\text{A}$		6.4	8.5	mΩ
		$V_{GS} = 10\text{V}, I_D = 20\text{A}$		5.1	7.5	

NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P0706BD

TO-252

Halogen-Free & Lead-Free

Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 20A$		48		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		3844		pF
Output Capacitance	C_{oss}			423		
Reverse Transfer Capacitance	C_{rss}			355		
Gate Resistance	R_g		$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	0.6		Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 30V, I_D = 20A$		106		nC
Gate-Source Charge ²	$Q_{g(VGS=4.5V)}$			58		
Gate-Drain Charge ²	Q_{gd}			14		
Turn-On Delay Time ²	$t_{d(on)}$			42		
Rise Time ²	t_r	$V_{DS} = 30V$ $I_D \geq 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$		28		nS
Turn-Off Delay Time ²	$t_{d(off)}$			50		
Fall Time ²	t_f			136		
				81		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				80	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 20A, dI_F/dt = 100A / \mu S$		41		nS
Reverse Recovery Charge	Q_{rr}			40		nC

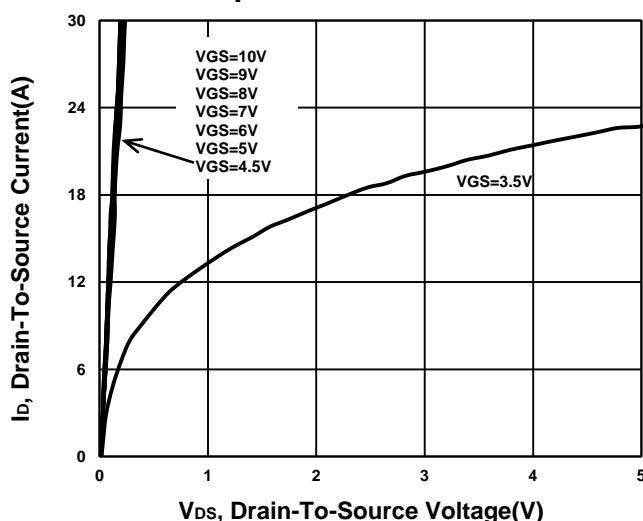
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current is 55A

NIKO-SEM

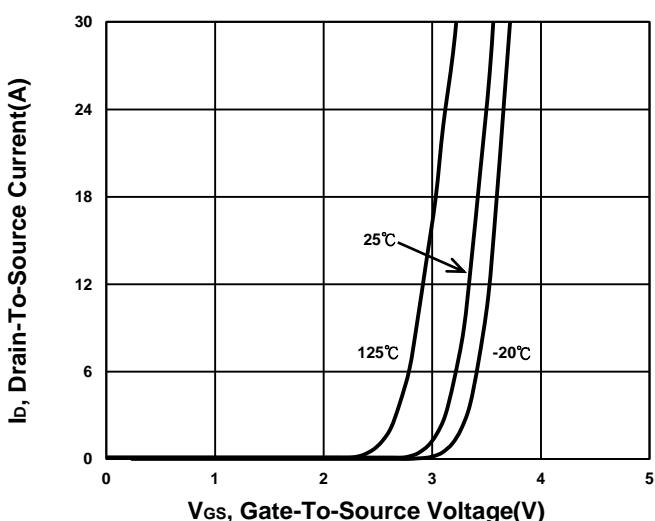
**N-Channel Enhancement Mode
Field Effect Transistor**

P0706BD
TO-252
Halogen-Free & Lead-Free

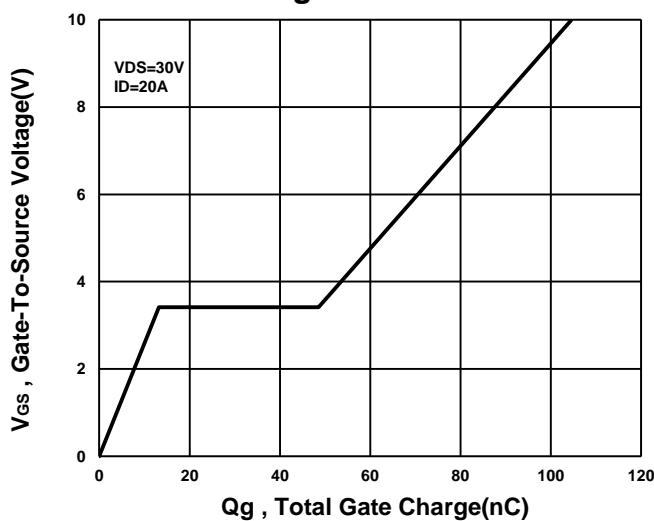
Output Characteristics



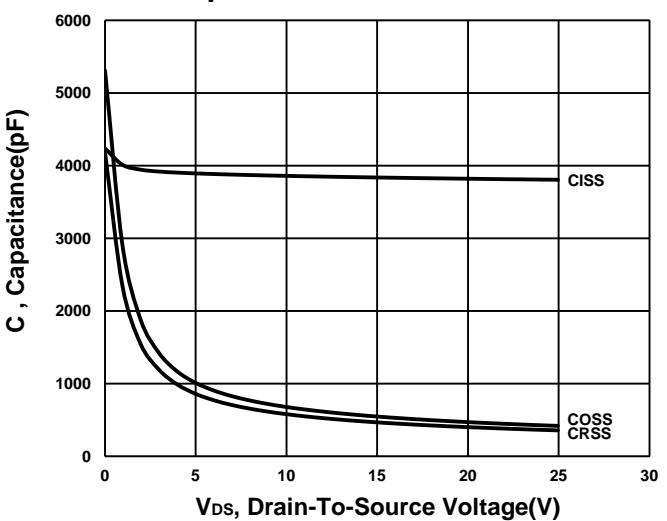
Transfer Characteristics



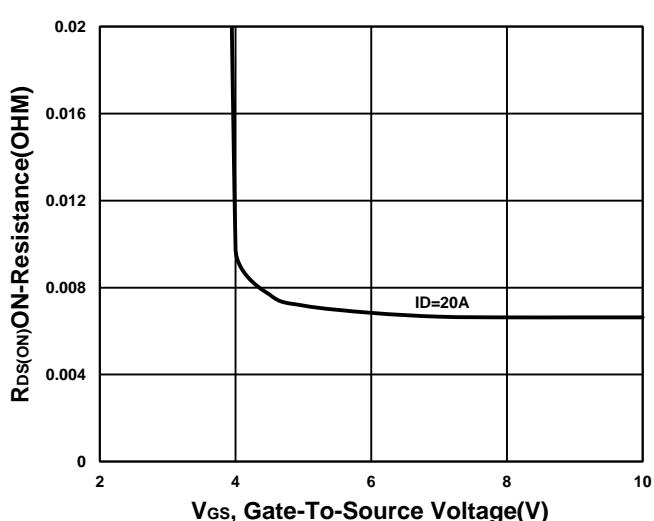
Gate charge Characteristics



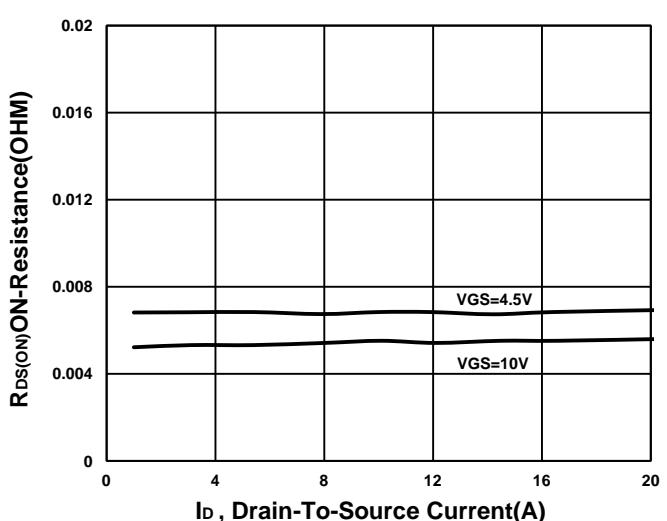
Capacitance Characteristic



On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
**P0706BD
TO-252
Halogen-Free & Lead-Free**
